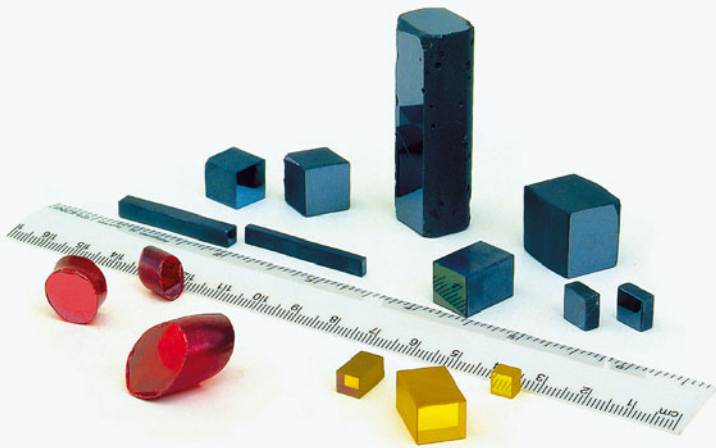


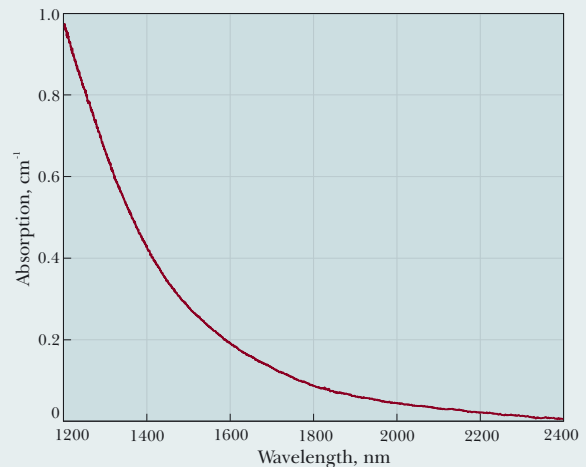
Infrared Nonlinear Crystals



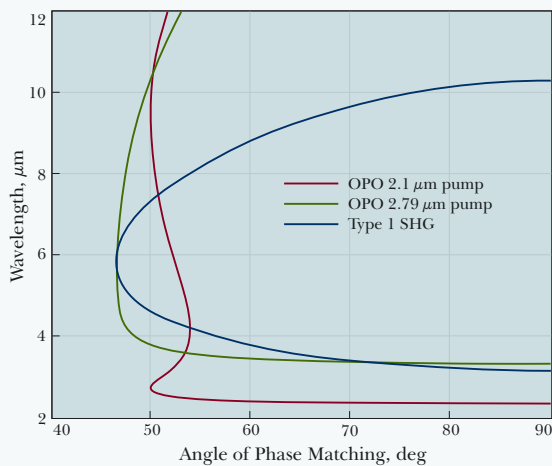
Optical nonlinear crystals like ZnGeP_2 , AgGaSe_2 , AgGaS_2 , GaSe have gained tremendous interest for the middle and deep infrared applications due to their unique features. The crystals have large effective optical nonlinearity, wide spectral and angular acceptances, broad transparency range, non-critical requirements for temperature stabilization and vibration control, are well mechanically processed (except of GaSe).

ZnGeP_2 has band edges at 0.74 and 12 μm with useful transmission range from 1.9 to 10.6 μm . ZnGeP_2 has the largest nonlinear optical coefficient and relatively high laser damage threshold. It was successfully used in the following applications: up-conversion of CO_2 laser light to near IR range⁽¹⁾ via mixing with 10.6 μm ; sum frequency generation of CO and CO_2 laser radiation⁽²⁾; efficient SHG of pulsed CO ⁽³⁾, CO_2 ⁽⁴⁾ and chemical DF-laser⁽⁵⁾, OPO light generation in mid infrared when pumped by erbium^(6,7) and holmium⁽⁸⁾ lasers.

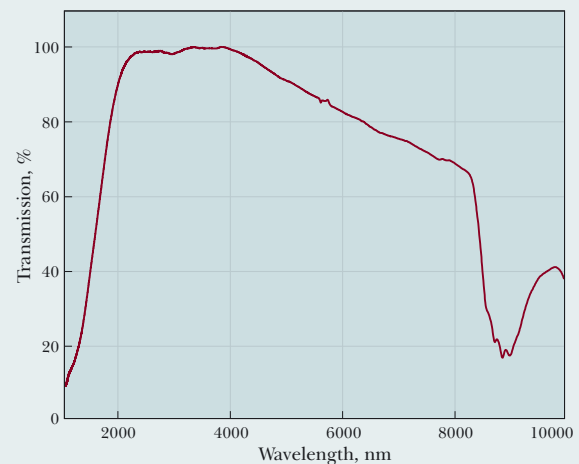
Crystals with lowest absorption $< 0.04 \text{ cm}^{-1}$ @ 2.1 μm are available from our company for better suitability for OPO or OPA application, then pumping 2.05–2.1 μm , with antireflection coatings.



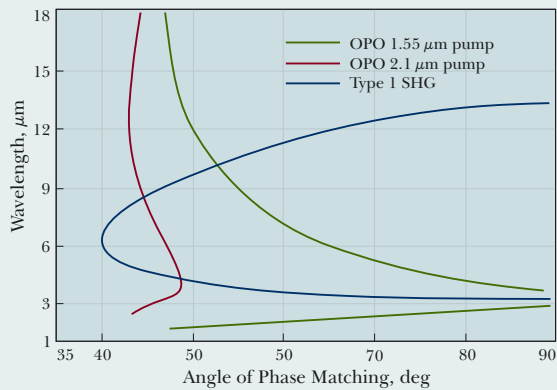
Absorption spectra of ZnGeP_2 crystal near 2 μm



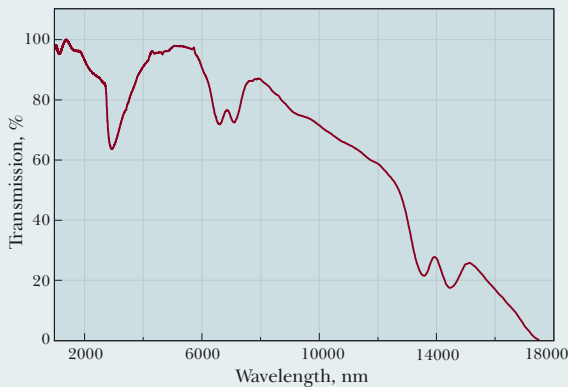
Type 1 OPO and SHG tuning curves in ZnGeP_2



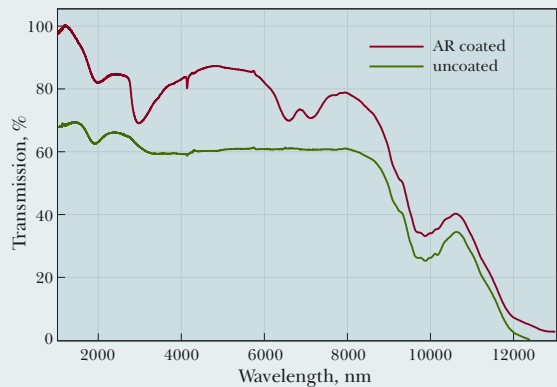
Transmission spectra of 15 mm long AR coated ZnGeP_2 crystal for OPO @ 2.1 μm



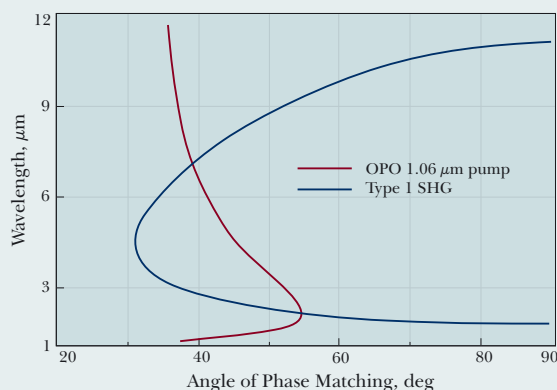
Type 1 OPO and SHG tuning curves in AgGaSe₂



Transmission spectra of 25 mm long AR coated AgGaSe₂ crystal



Transmission spectra of 14 mm long AR coated and uncoated AgGaSe₂ crystal used for OPO pumped by Nd:YAG laser

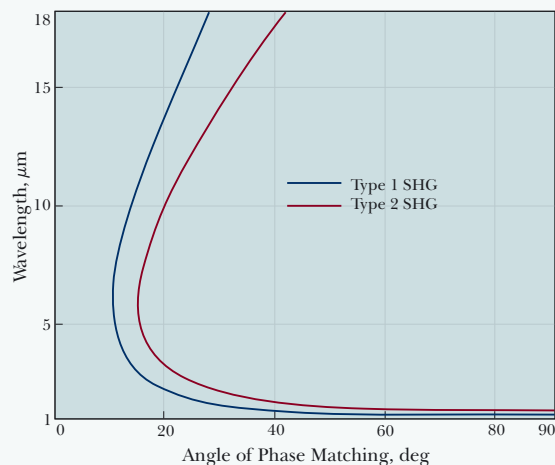


Type 1 OPO and SHG tuning curves in AgGaSe₂

AgGaSe₂⁽⁹⁾ has band edges at 0.73 and 18 μm. Its useful transmission range lying within 0.9–16 μm and wide phase match ability provide excellent potential for OPO applications when pumped by variety of currently available lasers. Tuning within 2.5–12 μm was obtained when pumped by Ho:YLF laser at 2.05 μm⁽¹⁰⁾; NCPM operation within 1.9–5.5 μm was achieved⁽¹¹⁾ pumping at 1.4–1.55 μm. Efficient SHG of pulsed CO₂ laser is demonstrated⁽¹²⁾.

AgGaSe₂ is transparent from 0.53 to 12 μm. Although nonlinear optical coefficient is the lowest among the above mentioned infrared crystals, its high short wavelength transparency edging at 550 nm is used in OPOs^(13,14) pumped by Nd:YAG laser; in numerous difference frequency mixing experiments^(15,16,17,18) using diode, Ti:Sapphire, Nd:YAG and IR dye lasers covering 3–12 μm range; direct infrared countermeasure systems, and SHG of CO₂ laser⁽¹⁹⁾.

GaSe has band edges at 0.65 and 18 μm. GaSe has been successfully used for efficient SHG of CO₂ laser⁽²¹⁾, for SHG of pulsed CO, CO₂ and chemical DF-laser (λ = 2.36 μm) radiation⁽²⁷⁾; up conversion of CO and CO₂ laser radiation into the visible range⁽²⁰⁾; infrared pulses generation via difference frequency mixing of Neodymium and infrared dye laser^(22,15) or (F-)centre laser pulses⁽²⁵⁾; OPG light generation within 3.5–18 μm⁽²⁴⁾; efficient TeraHertz generation in 100–1600 μm range⁽³⁹⁾. It is impossible to cut crystals for certain phase matching angles because of material structure (cleave along (001) plane) limiting areas of applications.



Type 1 and Type 2 SHG tuning curves in GaSe

Properties of ZnGeP₂, AgGaSe₂, AgGaS₂, GaSe

		ZnGeP ₂	AgGaSe ₂	AgGaS ₂	GaSe
CRYSTAL DATA					
Crystal Symmetry		Tetragonal	Tetragonal	Tetragonal	Hexagonal
Point Group		42m	42m	42m	62m
Lattice Constants, Å	a	5.465	5.9901	5.757	3.742
	c	10.771	10.8823	10.305	15.918
Density, g/cm ³		4.175	5.71	4.56	5.03
OPTICAL PROPERTIES					
Optical transmission, μm		0.74 ÷ 12 ⁽²³⁾	0.73 ÷ 18 ⁽⁹⁾	0.53 ÷ 12 ⁽³²⁾	0.65 ÷ 18 ⁽²⁷⁾
Indices of Refraction at					
1.06 μm	n _o	3.2324	2.7005	2.4508	2.9082
	n _e	3.2786	2.6759	2.3966	2.5676
5.3 μm	n _o	3.1141	2.6140	2.3954	2.8340
	n _e	3.1524	2.5823	2.3421	2.4599
10.6 μm	n _o	3.0725	2.5915	2.3466	2.8158
	n _e	3.1119	2.5585	2.2924	2.4392
Absorption Coefficient, cm ⁻¹ at					
1.06 μm		3.0 ⁽²⁸⁾	<0.02 ⁽⁹⁾	<0.09	0.25 ⁽⁶⁾
2.5 μm		0.03 ⁽²⁸⁾	<0.01	0.01	0.05 ⁽⁶⁾
5.0 μm		0.02 ⁽²⁸⁾	<0.01	0.01	0.05 ⁽⁶⁾
7.5 μm		0.02 ⁽²⁸⁾	-	0.02	0.05 ⁽⁶⁾
10.0 μm		0.4 ⁽²⁸⁾	-	<0.6	0.05 ⁽⁶⁾
11.0 μm		0.8 ⁽²⁸⁾	-	0.6	0.05 ⁽⁶⁾
NONLINEAR OPTICAL PROPERTIES					
Laser damage threshold, MW/cm ²		60 ⁽²⁹⁾	25 ⁽³⁸⁾	10 ⁽¹³⁾	28 ⁽²¹⁾
at pulse duration, ns		100	50	20	150
at wavelength, μm		10.6	2.05	1.06	9.3
Nonlinearity, pm/V		111 ⁽²¹⁾	43 ⁽¹¹⁾	31 ⁽³⁴⁾	63 ⁽²¹⁾
Phase matching angle for Type 1 SHG at 10.6 μm, deg		76	55	67	14
Walk-off angle at 5.3 μm, deg		0.57 ⁽²¹⁾	0.67 ⁽¹¹⁾	0.85 ⁽¹⁹⁾	3.4 ⁽²¹⁾
THERMAL PROPERTIES					
Melting point, °C		1298 ⁽³⁰⁾	851 ⁽¹²⁾	998 ⁽²⁶⁾	1233
Thermal Expansion Coefficient, 10 ⁻⁶ /°K					
	⊥	17.5 ^(31,a)	23.4 ^(33,c)	12.5 ⁽³⁵⁾	9.0
	⊥	9.1 ^(31,b)	18.0 ^(33,d)		
		1.59 ^(31,a)	-6.4 ^(33,c)	-13.2 ⁽³⁵⁾	8.25
		8.08 ^(31,b)	-16.0 ^(33,d)		

a) at 293-573 K, b) at 573-873 K, c) at 298-423 K, d) at 423-873 K

SELLMEIER EQUATIONS FOR CALCULATION OF INDICES OF REFRACTION

Crystal		A	B	C	D	E	F	Ref.	Expression
ZnGeP₂	n _o	8.0409	1.68625	0.40824	1.2880	611.05	-	37	n ² = A + B λ ² / (λ ² - C) + + D λ ² / (λ ² - E)
	n _e	8.0929	1.8649	0.41468	0.84052	452.05	-		
AgGaSe₂	n _o	6.8507	0.4297	0.15840	0.00125	-	-	36	n ² = A + B / (λ ² - C) - D λ ²
	n _e	6.6792	0.4598	0.21220	0.00126	-	-		
AgGaS₂	n _o	3.3970	2.3982	0.09311	2.1640	950.0	-	13	n ² = A + B / (1 - C / λ ²) + + D / (1 - E / λ ²)
	n _e	3.5873	1.9533	0.11066	2.3391	1030.7	-		
GaSe	n _o	7.443	0.405	0.0186	0.0061	3.1485	2194	4	n ² = A + B / λ ² + C / λ ⁴ + + D / λ ⁶ + E / (1 - F / λ ²)
	n _e	5.76	0.3879	-0.2288	0.1223	1.855	1780		

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